T2G6003028-FS

30 W, 28V DC – 6 GHz, GaN RF Power Transistor

Product Overview

The Qorvo T2G6003028-FS is a 30W (P_{3dB}) discrete GaN on SiC HEMT which operates from DC to 6 GHz. The device is constructed with Qorvo's proven QGaN25 process, which features advanced field plate techniques to optimize power and efficiency at high drain bias operating conditions. This optimization can potentially lower system costs in terms of fewer amplifier line-ups and lower thermal management costs.

Lead-free and ROHS compliant

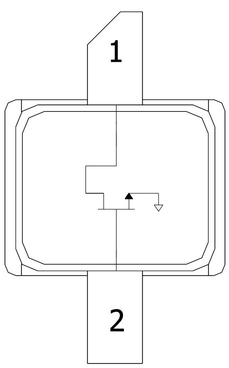
Evaluation boards are available upon request.

Key Features [1]

- Frequency: DC to 6 GHz
- Output Power (P_{3dB}): 42.7 W
- Linear Gain: >14 dB
- Operating Voltage: 28 V
- Low thermal resistance package
- Pulse capable

  Note 1: @ 3 GHz

Functional Block Diagram



Applications

- Military radar
- Civilian radar
- Professional and military radio communications
- Test instrumentation
- Wideband or narrowband amplifiers
- Jammers

Pin Configuration

Pin No.	Label
1	V_D / RF OUT
2	V_G / RF IN
3	Flange/Source

Ordering info

Part No.	Description
T2G6003028-FS	Packaged part Flangeless
T2G6003028-FSEVB	5.4 – 5.9 GHz Evaluation Board
T2G6003028-FSEVB2	1.3 – 1.9 GHz Evaluation Board

Absolute Maximum Ratings

Parameter	Rating	Units
Breakdown Voltage, BV_{DG}	100	V
Gate Voltage Range, V_G	-7 to +2	V
Drain Current, I_{DMAX}	5.5	A
Gate Current Range, I_G	-10 to 28	mA
Power Dissipation, Pulsed, P_{DISS} [2]	47.5	W
RF Input Power, CW, T = 25°C (P_{IN})	40	dBm
Channel Temperature (T_{CH})	275	°C
Mounting Temperature (30 Seconds)	320	°C
Storage Temperature	−40 to +150	°C

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

Recommended Operating Conditions [1, 2]

Parameter	Min	Typ	Max	Units
Drain Voltage Range, V_D	12		40	V
Drain Bias Current, I_{DQ}		200		mA
Gate Voltage, V_G	–	−3.0	–	V

Electrical Specifications [1, 2]

Parameter	Min	Typ	Max	Units
Linear Gain, G_{LIN}	12	14	–	dB
Output Power at 3dB compression point, P3dB	43.0	44.6	–	W
Drain Efficiency at 3dB compression point, DEFF3dB	45.0	54.0	–	%
Gain at 3dB compression point, G3dB	9.0	11.0	–	dB
Gate Leakage (V_D = +10 V, V_G = −3.7 V)	-11	–	–	mA

Notes:
1. Performance at 5.6 GHz in the 5.4 to 5.9 GHz Evaluation Board
2. V_{DS} = 28 V, I_{DQ} = 200 mA; Pulse: 100µs, 20%

RF Characterization – Mismatch Ruggedness at 5.6 GHz [1]

Symbol	Parameter	dB Compression	Typical
VSWR	Impedance Mismatch Ruggedness	3	10:1

Notes:
1. P_{1dB} CW Input Power under matched condition.

Power-Matched Load Pull Performance

Test conditions unless otherwise noted: T = 25°C.

Parameter	Typical Value						Units
Frequency (F)	1	2	3	4	5	6	GHz
Drain Voltage (V_D)	28	28	28	28	28	28	V
Bias Current (I_{DQ})	200	200	200	200	200	200	mA
Output P3dB (P_{3dB})	45.7	46	46.3	46.5	46.8	46.2	dBm
PAE @ P_{3dB} (PAE_{3dB})	64.9	64.2	68.1	54.6	55.9	54.7	%
Gain @ P3dB (G_{3dB})	19.9	15.7	11.3	10.1	10.7	12.1	dB

Notes:

1. V_D = 28 V, I_{DQ} = 200 mA, Pulse Width = 100 uS, Duty Cycle = 20%
2. Characteristic Impedance (Z_o) = 10 Ω. See pg. 14 for Load Pull Reference Planes.

Efficiency-Matched Load Pull Performance

Test conditions unless otherwise noted: T = 25°C.

Parameter	Typical Value						Units
Frequency (F)	1	2	3	4	5	6	GHz
Drain Voltage (V_D)	28	28	28	28	28	28	V
Bias Current (I_{DQ})	200	200	200	200	200	200	mA
Output P3dB (P_{3dB})	43.1	43.1	44.6	44.1	44.9	45.7	dBm
PAE @ P_{3dB} (PAE_{3dB})	73	76	46.1	65.1	69.5	60	%
Gain @ P3dB (G_{3dB})	19.7	16.2	11.7	10.8	12.4	12.9	dB

Notes:

1. V_D = 28 V, I_{DQ} = 200 mA, Pulse Width = 100 uS, Duty Cycle = 20%.
2. Characteristic Impedance (Z_o) = 10 Ω. See pg. 14 for Load Pull Reference Planes.

Thermal Information – CW [1, 2]

Parameter	Test Conditions	Value	Units
Thermal Resistance, IR[2] (θ_{JC})	P_D = 30 W, Tbase = 85°C	2.51	°C/W
Maximum Channel Temperature, T_{CH}		160.65	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 35 W, Tbase = 85°C	2.58	°C/W
Maximum Channel Temperature, T_{CH}		175.20	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 40 W, Tbase = 85°C	2.67	°C/W
Maximum Channel Temperature, T_{CH}		191.68	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 45 W, Tbase = 85°C	2.75	°C/W
Maximum Channel Temperature, T_{CH}		208.73	°C

Notes:

1. Thermal resistance calculated to bottom of package.
2. Refer to the following document: GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates

Thermal Information – Pulsed [1, 2]

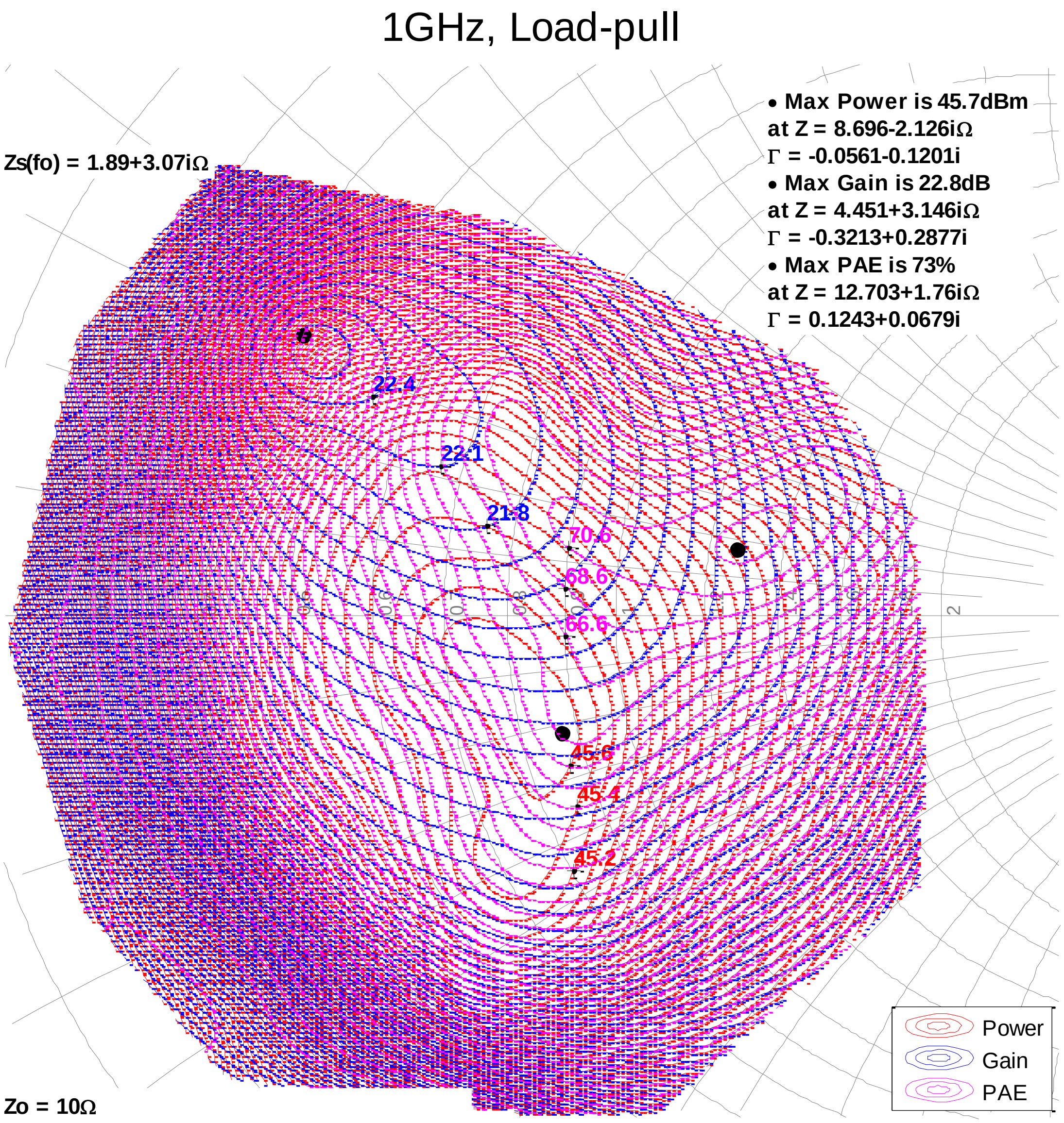
Parameter	Test Conditions	Value	Units
Thermal Resistance, IR[2] (θ_{JC})	P_D = 40 W, Tbase = 85°C Pulse Width = 100 uS Duty Cycle = 5%	1.56	°C/W
Peak Channel Temperature,T_{CH}		147.37	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 40 W, Tbase = 85°C Pulse Width = 100 uS Duty Cycle = 10%	1.62	°C/W
Peak Channel Temperature, T_{CH}		149.83	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 40 W, Tbase = 85°C Pulse Width = 100 uS Duty Cycle = 20%	1.77	°C/W
Peak Channel Temperature, T_{CH}		155.89	°C
Thermal Resistance, IR[2] (θ_{JC})	P_D = 40 W, Tbase = 85°C Pulse Width = 100 uS Duty Cycle = 50%	2.07	°C/W
Peak Channel Temperature, T_{CH}		167.69	°C

Notes:

1. Thermal resistance calculated to bottom of package.
2. Refer to the following document: GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates

Load Pull Contours [1, 2, 3]

Notes:
1. Test Conditions: V_{DS} = 28 V, I_{DQ} = 200 mA
2. Test Signal: Pulse Width = 100 µsec, Duty Cycle = 20%
3. See pg. 14 for load pull reference planes.



Load Pull Contours [1, 2, 3]

Notes:

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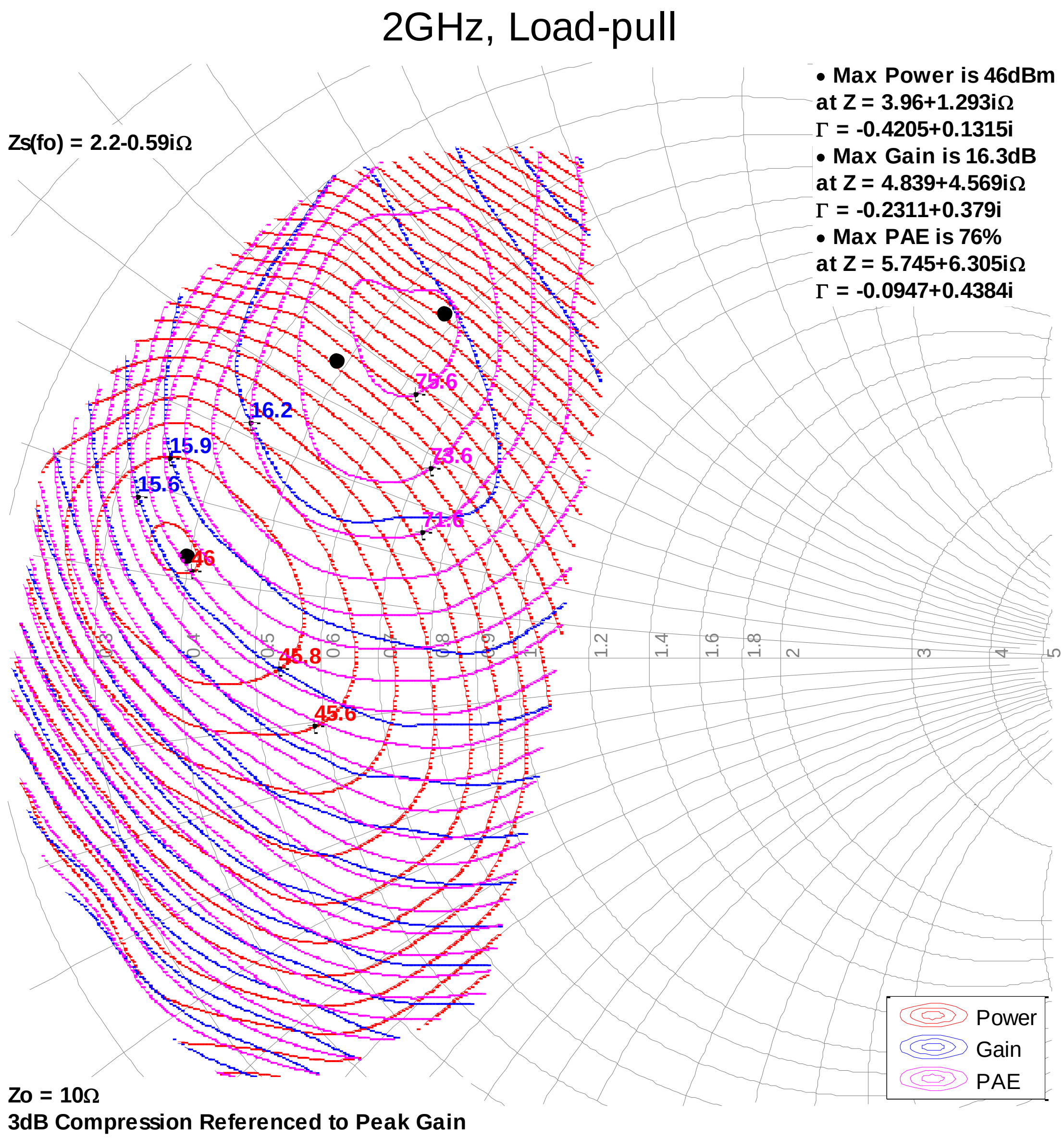

Load Pull Contours [1, 2, 3]

Notes:

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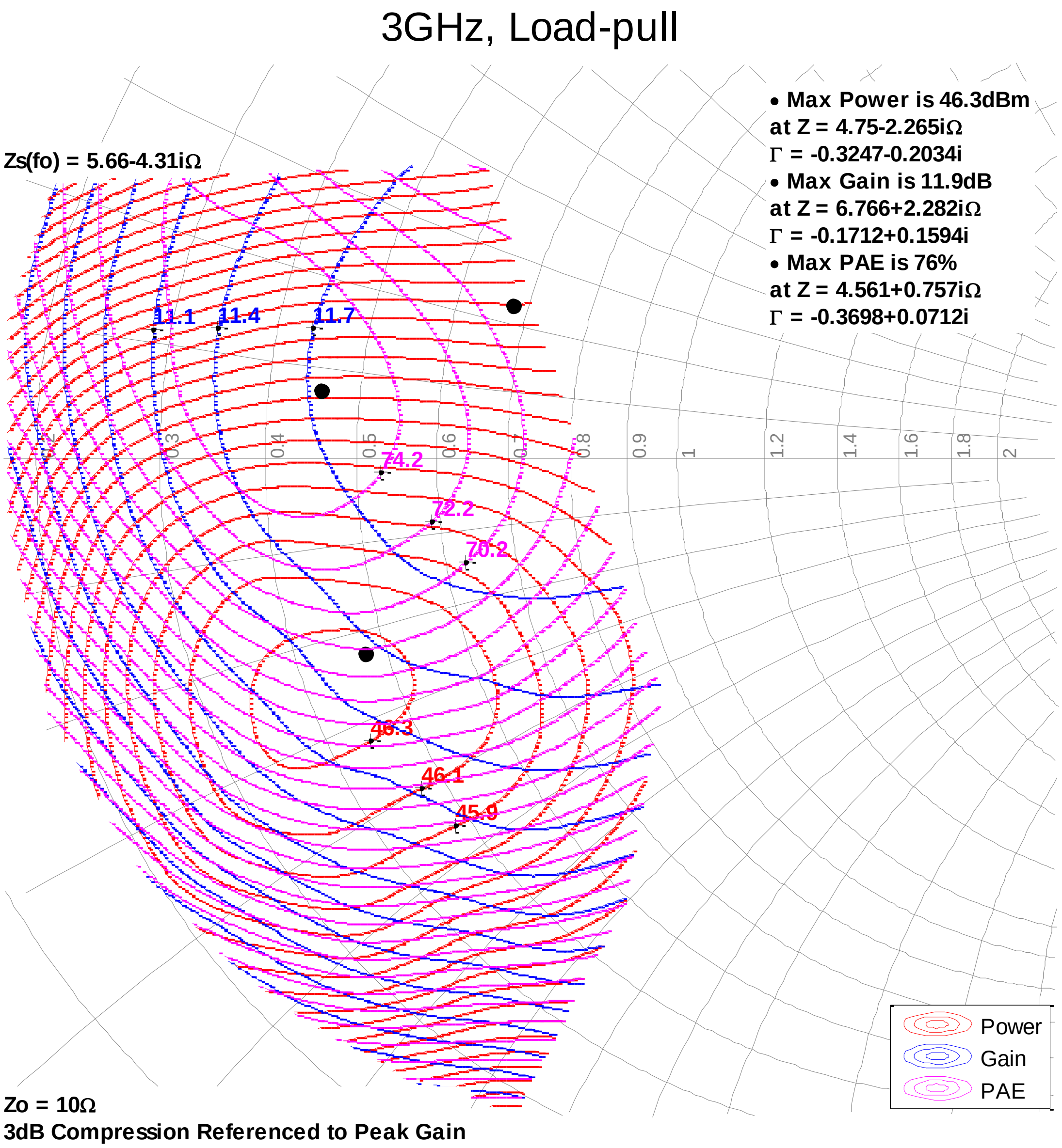

Load Pull Contours [1, 2, 3]

Notes:
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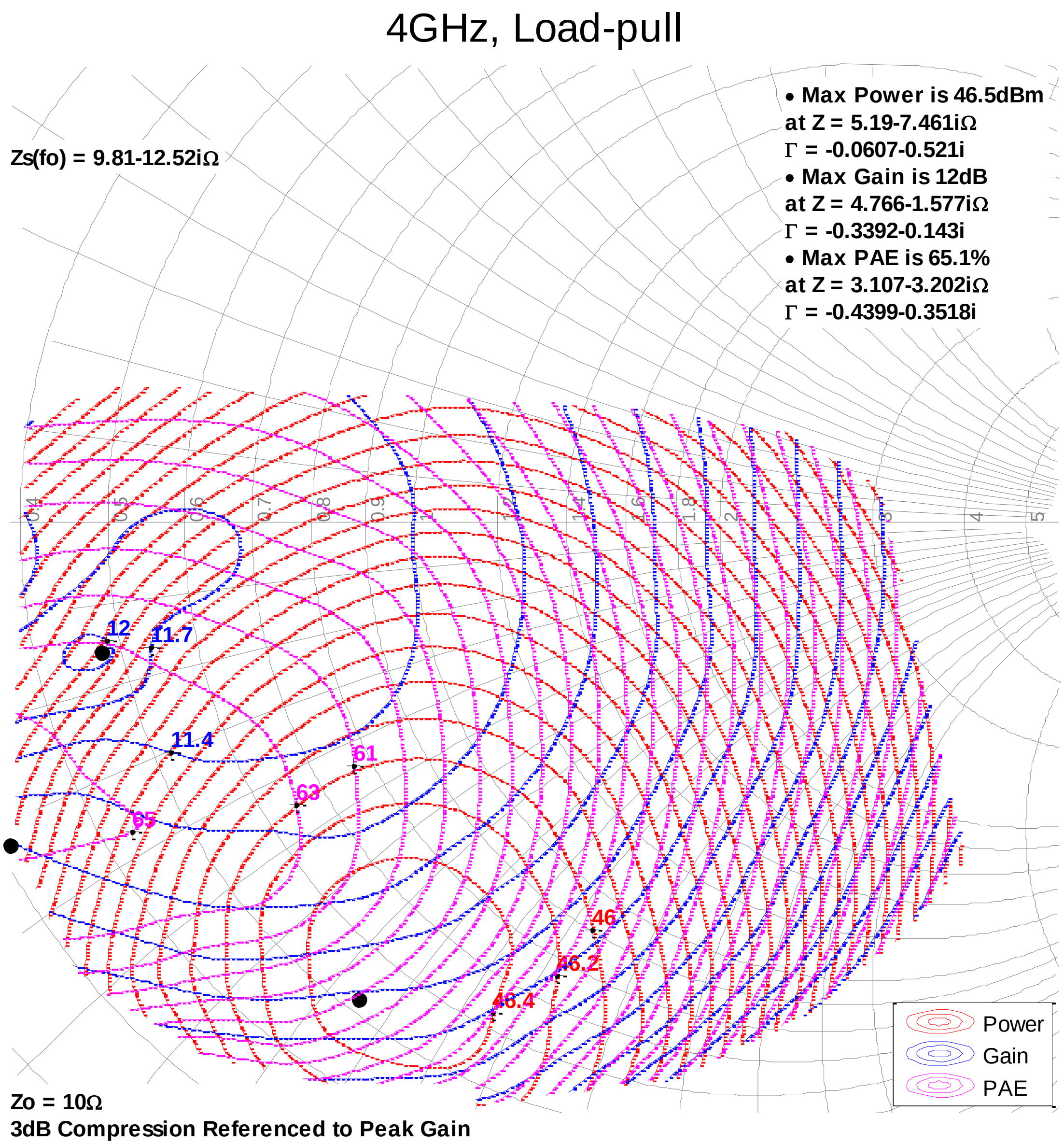

Load Pull Contours [1, 2, 3]

Notes:
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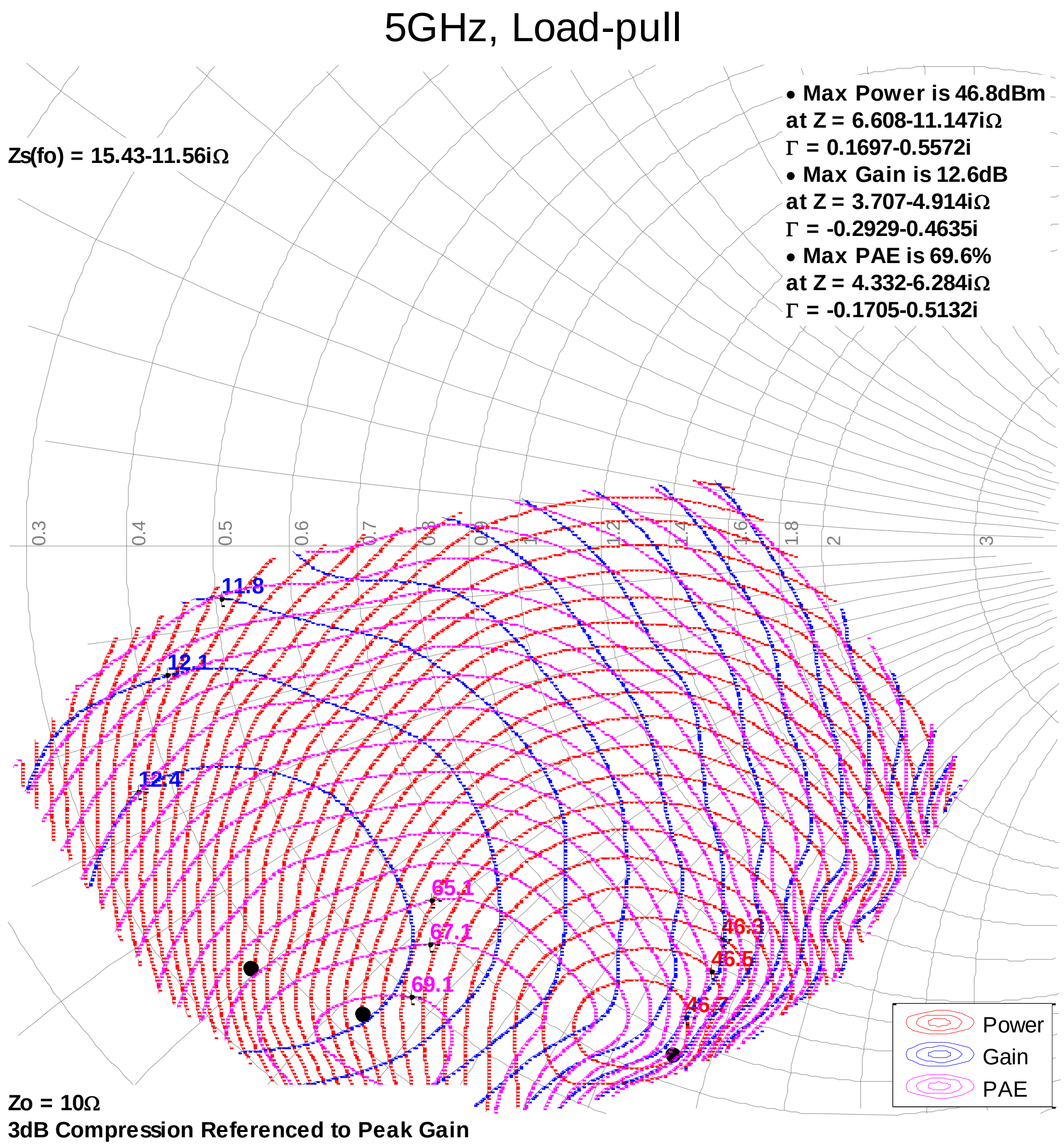
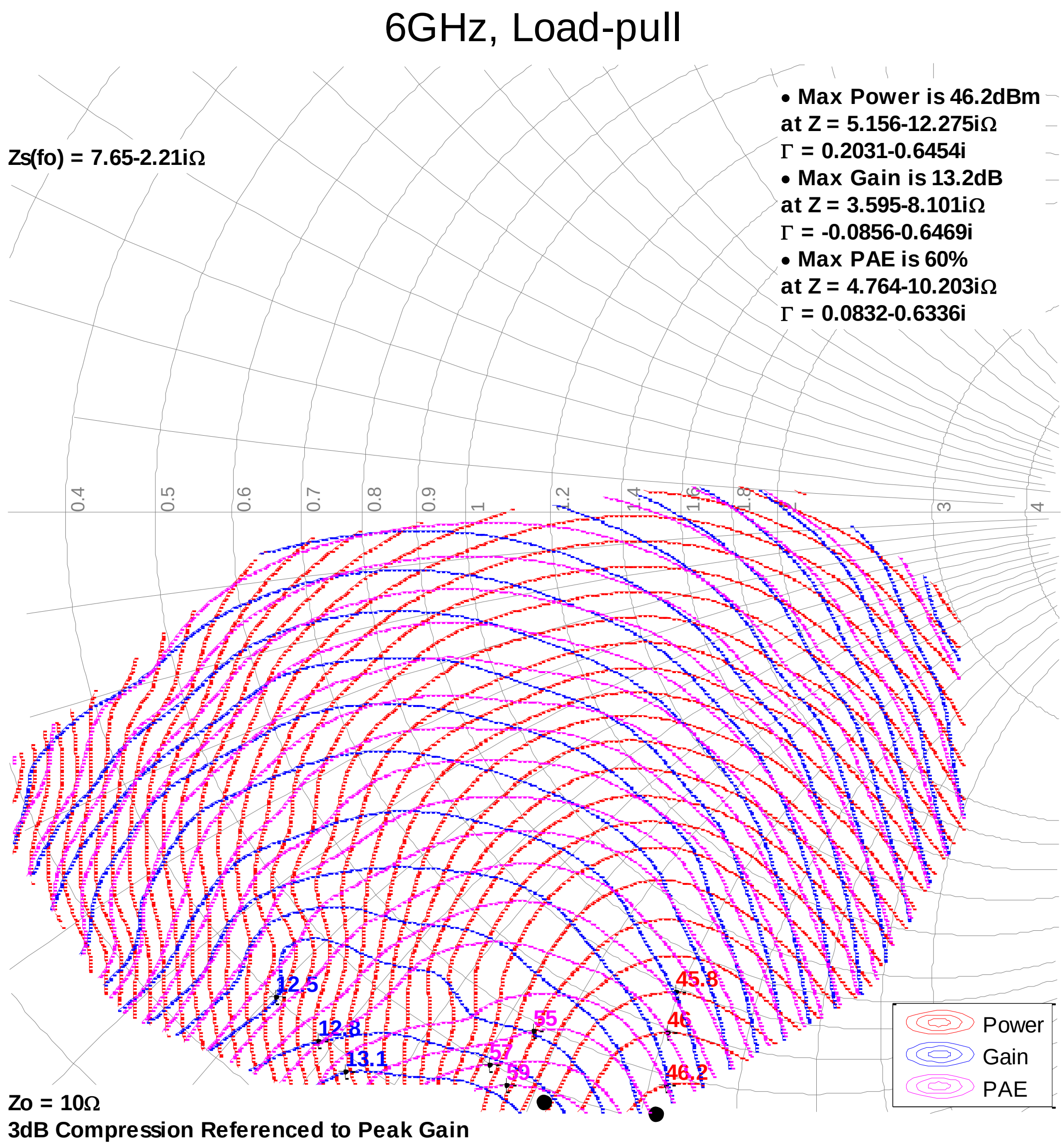
2. Test Signal: Pulse Width = 100 µsec, Duty Cycle = 20%
3. See pg. 14 for load pull reference planes.



Load Pull Contours [1, 2, 3]

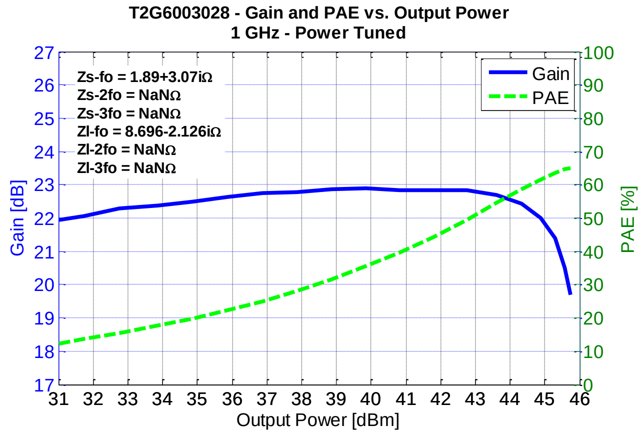
Notes:
1. Test Conditions: V_{DS} = 28 V, I_{DQ} = 200 mA
2. Test Signal: Pulse Width = 100 µsec, Duty Cycle = 20%
3. See pg. 14 for load pull reference planes.

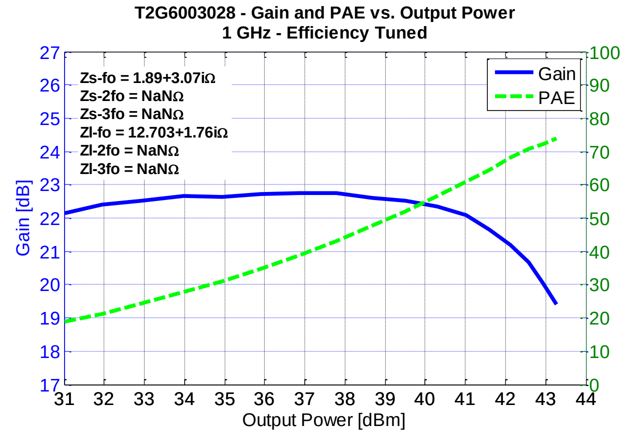


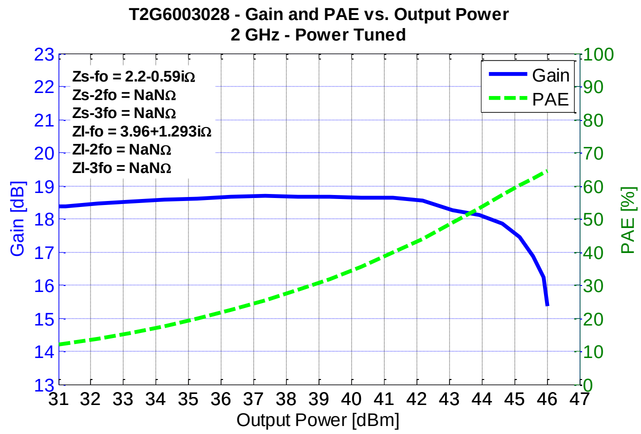
Load Pull Drive-up [1, 2]

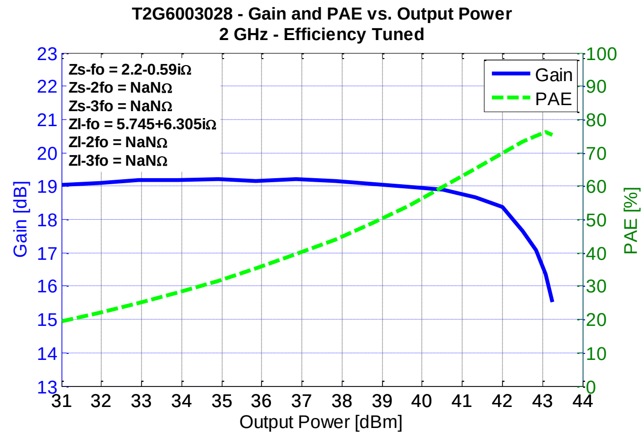
Notes:

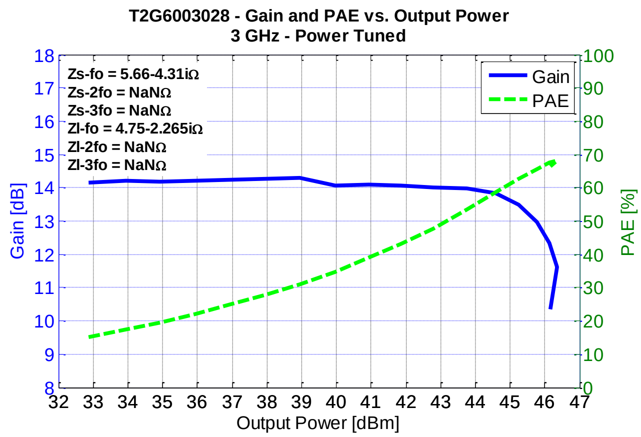
1. Vd = 28 V, Idq = 200 mA, Pulse Width = 100 uS, Duty Cycle = 20%
2. NaN means the parameter is either unavailable or undefined.

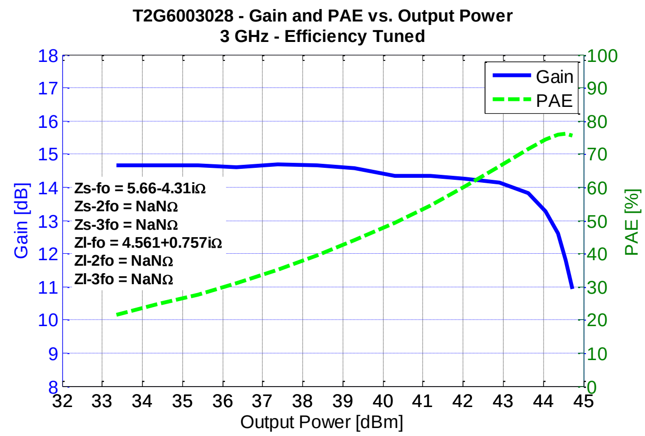








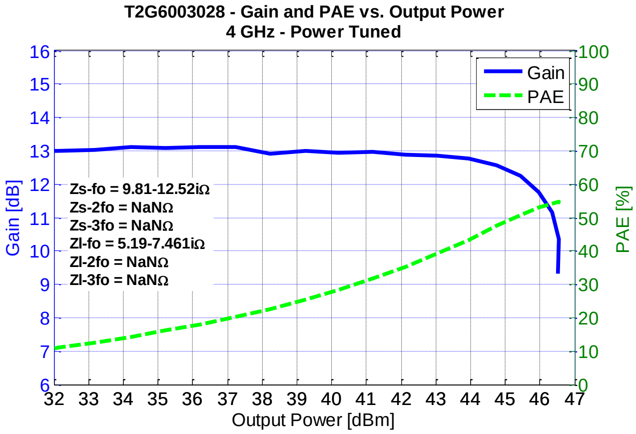


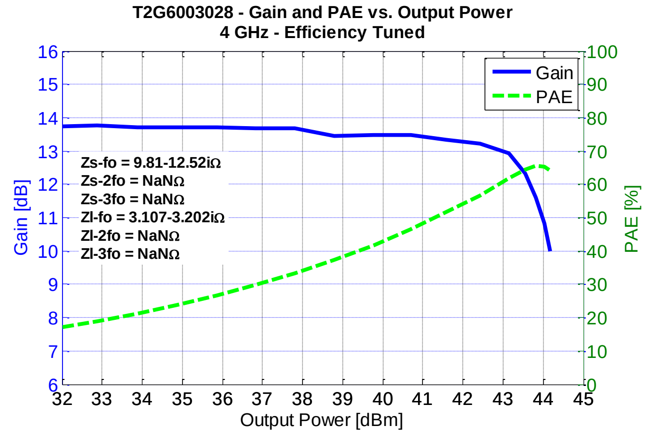


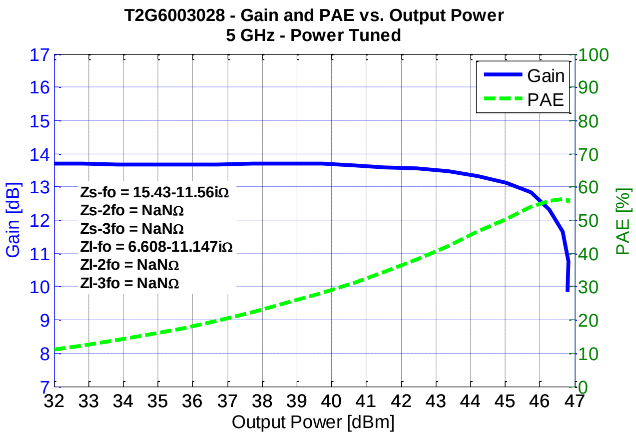
Load Pull Drive-up [1, 2]

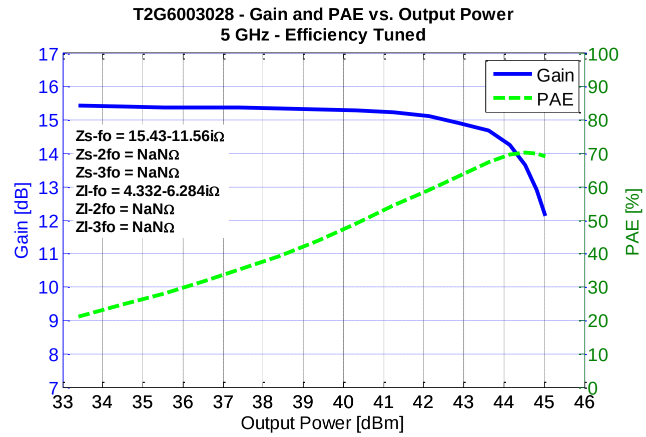
Notes:

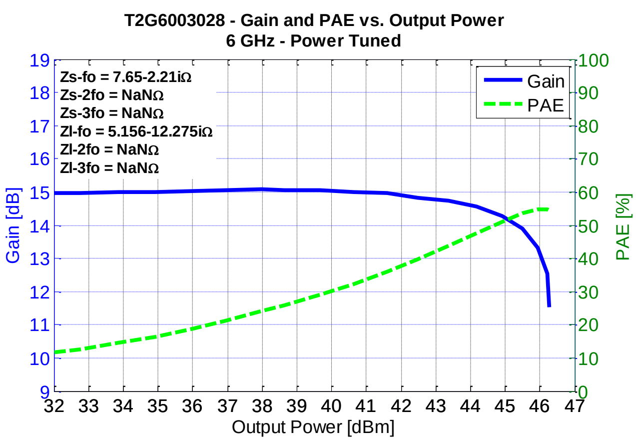
1. Vd = 28 V, Idq = 200 mA, Pulse Width = 100 uS, Duty Cycle = 20%
2. NaN means the parameter is either unavailable or undefined.

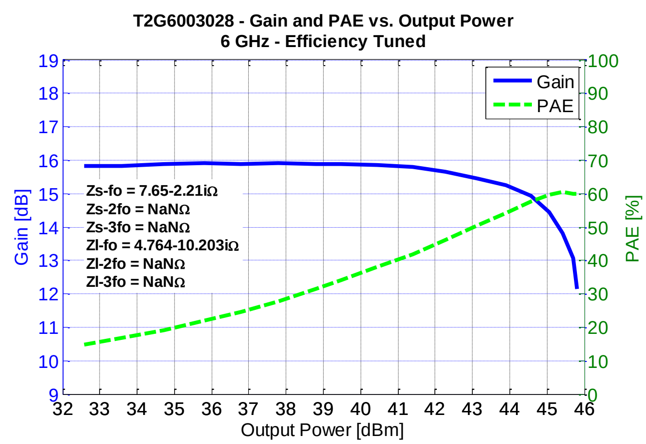




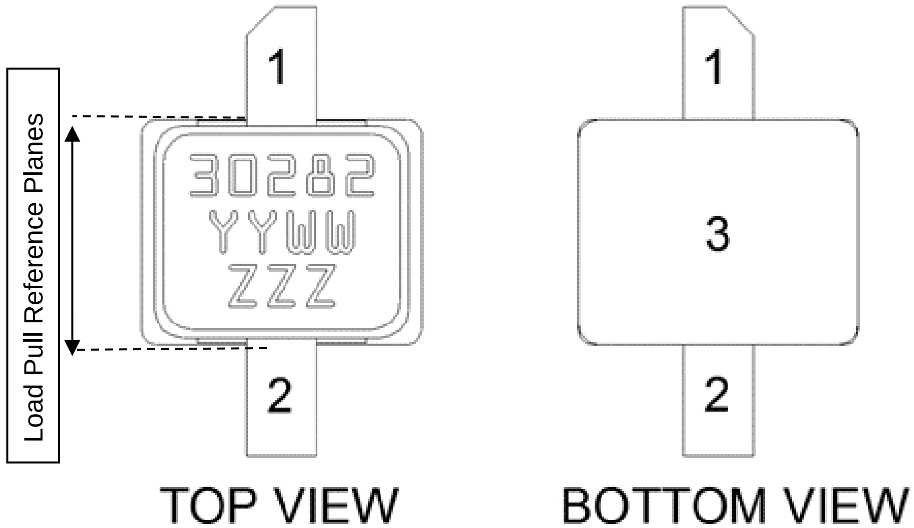








Package Marking and Pin Configuration [1]

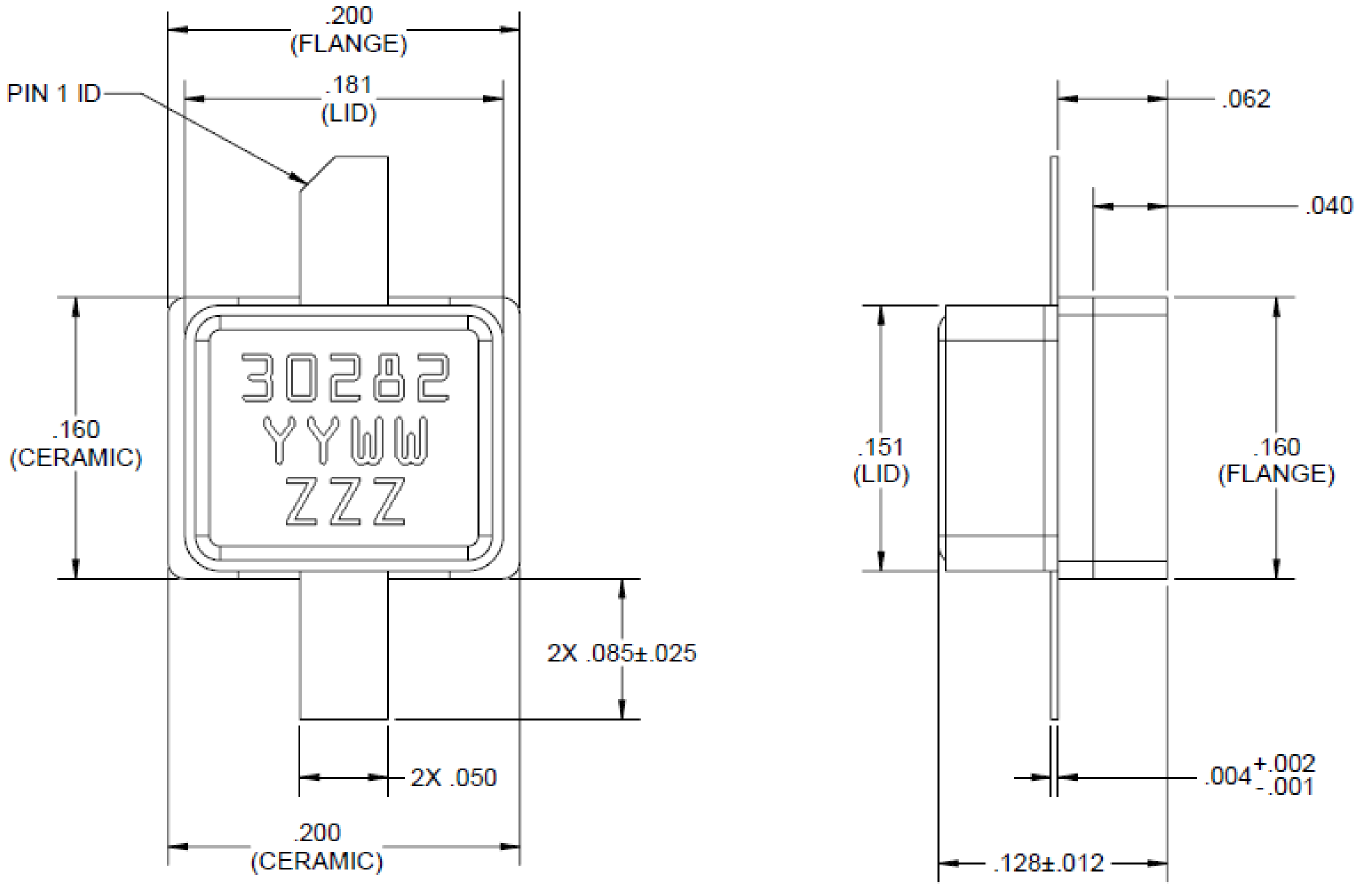


Note:
The T2G6003028-FS will be marked with the “30282” designator and a lot code marked below the part designator. The “YY” represents the last two digits of the calendar year the part was manufactured, the “WW” is the work week of the assembly lot start, and the “ZZZ” is an auto-generated number.

Pin	Symbol	Description
1	V_D / RF OUT	Drain voltage / RF Output matched to 50 ohms; see EVB Layout on page 17 as an example.
2	V_G / RF IN	Gate voltage / RF Input matched to 50 ohms; see EVB Layout on page 17 as an example.
3	Flange	Source connected to ground; see EVB Layout on page 17 as an example.

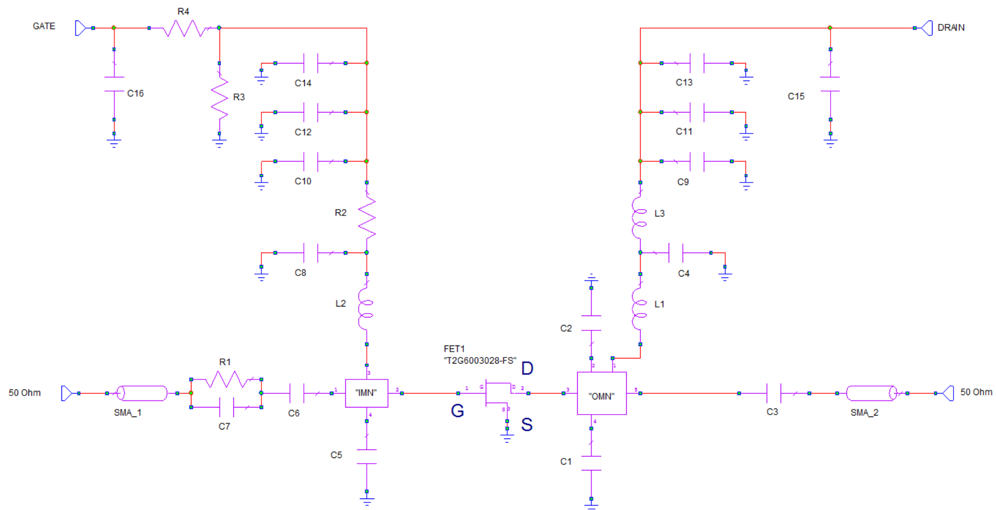
Notes:
Thermal resistance measured to bottom of package

Package Dimensions



Notes:
1. Material:
   Package Base: Ceramic/Metal
   Package Lid: Ceramic
2. Package exposed matellization is gold plated
3. Part is epoxy sealed
4. Part meets industry NI200 footprint
5. Body dimensions do not include lid shift or epoxy run out which can be up to 0.020 per side.
6. Dimensions are in inches. General tolerance is ±0.005”.

Application Circuit

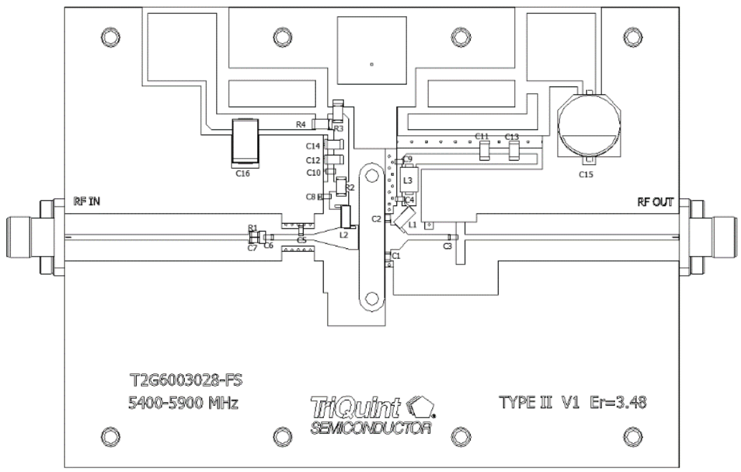


Bias Procedure

Bias-up Procedure	Bias-down Procedure
1. Set V_G to -5 V.	1. Turn off RF signal.
2. Set I_D current limit to 220 mA.	2. Turn off V_D
3. Apply 28 V V_D.	3. Wait 1 seconds to allow drain capacitor to discharge.
4. Slowly adjust V_G until I_D is set to 200 mA.	4. Turn off V_G
5. Set I_D to 2.8 A.	
6. Apply RF signal	

5.4 – 5.9 GHz Evaluation Board– Layout [1, 2, 3]

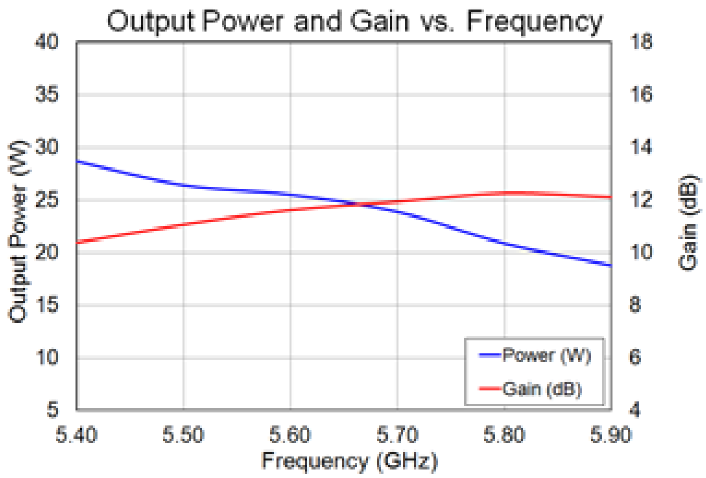
Notes:
1. Top RF layer is 0.020” thick Rogers RO4350B, ε_r = 3.48
2. The pad pattern shown has been developed and tested for optimized assembly at Qorvo Semiconductor.
3. The PCB land pattern has been developed to accommodate lead and package tolerances

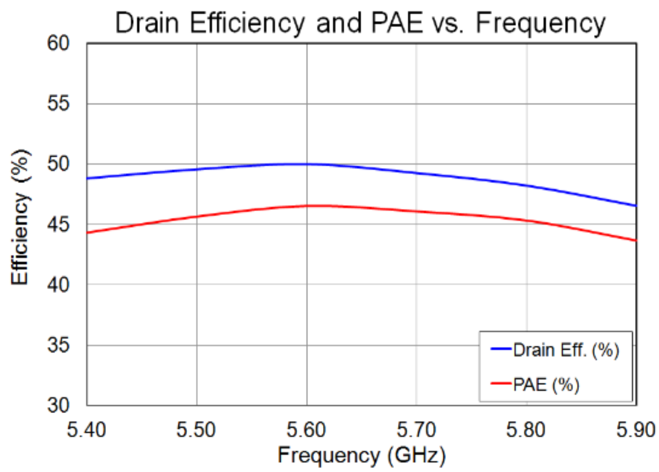


5.4 – 5.9 GHz Application Circuit – Bill of Materials EVB1

Ref Des	Qty	Description	Mfg Name	Mfg Part #
C1	1	0.3 pF	ATC	ATC600S0R3
C2	1	0.2 pF	ATC	ATC600S0R2
L1, L2	2	8.8 NH	COILCRAFT	1606-8
C3, C4, C6, C7, C8	5	3 pF	ATC	ATC600S3R0
C5	1	0.4 pF	ATC	ATC600S0R5
R1	1	97.6 Ohms	Venkel	CR0604-16w-97R6FT
R2	1	4.7 Ohms	Newark	37C0064
R3	1	330 Ohms	Newark	TNPW1206330RBT9ET1-E3
R4	1	50 Ohms	ATC	CRCW120651R0FKEA
C9, C10	2	220 pF	AVX	AVX06035C22KAT2A
C11, C12	2	2200 pF	Vitramon	VJ1206Y222KXA
C13, C14	2	22000 pF	Vitramon	VJ1206Y223KXA
C15	1	220 uF	United Chemi-Con	EMVY500ADA221MJA0G
C16	1	1.0 uF	Allied	541-1231
L3	1	48 Ohm	Ferrite, Laird Tech.	28F0121-0SR-10

Evaluation Board Performance [1, 2, 3]



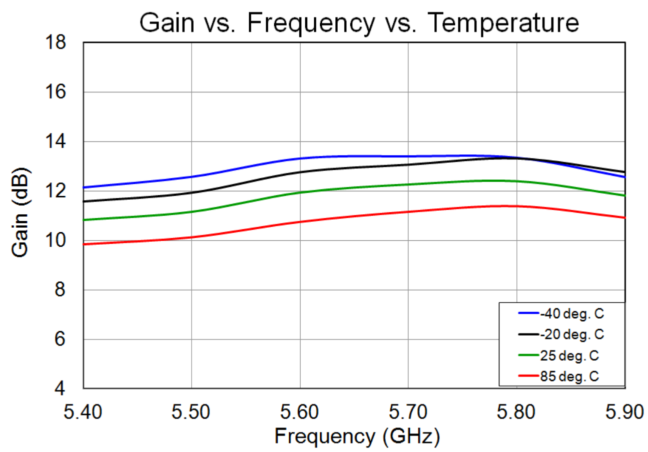


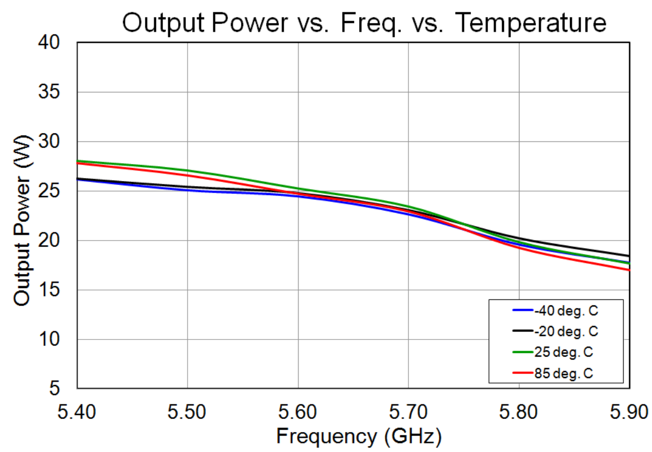
Notes:

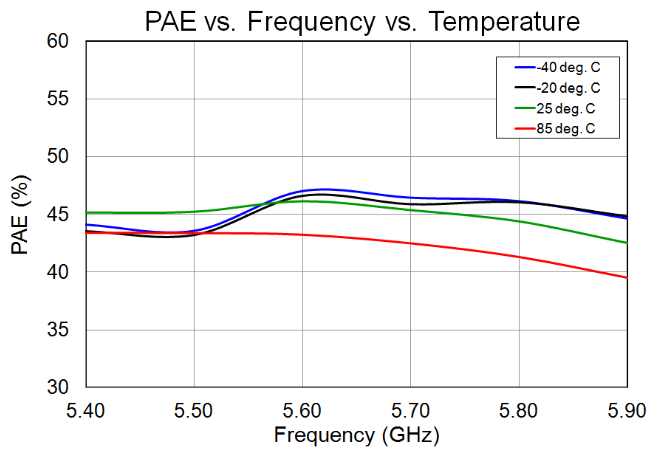
1. Test Conditions: V_{DS} = 28 V, I_{DQ} = 200 mA
2. Test Signal: Pulse Width = 100 µs, Duty Cycle = 20 %
3. Performance at 3dB compression.

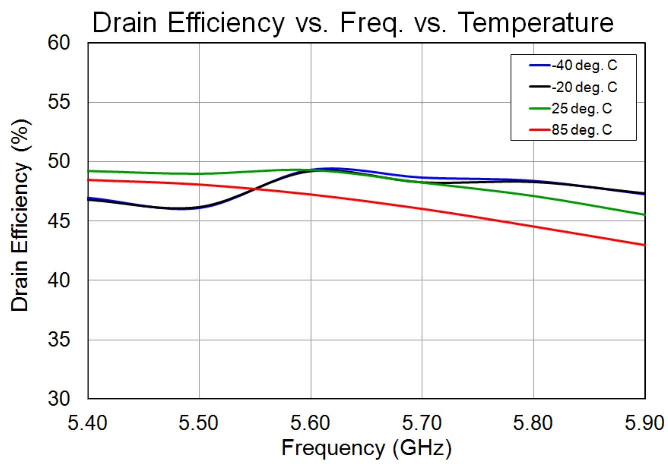
Performance over Temperatures of 5.4 – 5.9 GHz EVB [1, 2]

Notes:
1. Test Conditions: V_D = 28 V, I_{DQ} = 200 mA, 100 us Pulse Width, 20% Duty Cycle.
2. Performance at 3dB compression.

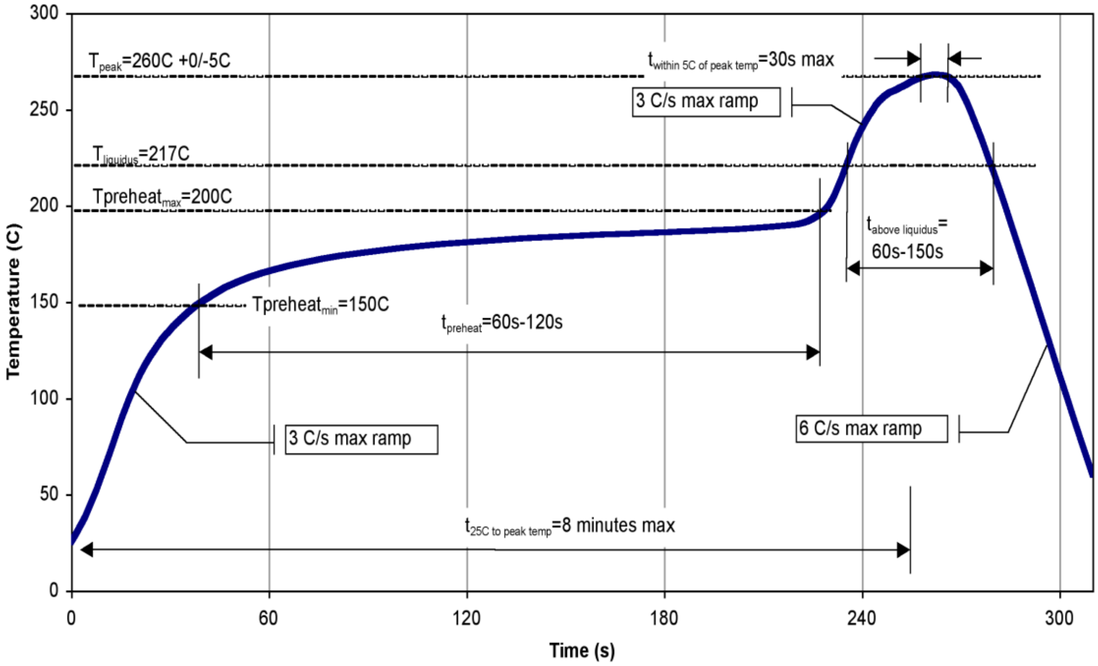








Recommended Solder Temperature Profile



Handling Precautions

Parameter	Rating	Standard
ESD – Human Body Model (HBM)	Class 1A (250V)	JEDEC JESD22-A114
ESD – Charged Device Model (CDM)	Class C3 (1000V)	JEDEC JS-002
MSL – Moisture Sensitivity Level	MSL3	JESD J-STD-020

Caution!
ESD-Sensitive Device

Solderability

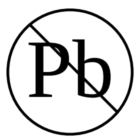
Compatible with both lead-free (260°C max. reflow temp.) and tin/lead (245°C max. reflow temp.) soldering processes.
Solder profiles available upon request.
The use of no-clean solder to avoid washing after soldering is recommended.
Contact plating: NiAu. Minimum Au thickness is 60 µinches.

RoHS Compliance

This part is compliant with 2011/65/EU RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment) as amended by Directive 2015/863/EU.

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A ($C_{15}H_{12}Br_4O_2$) Free
- PFOS Free
- SVHC Free



Contact Information

For the latest specifications, additional product information, worldwide sales and distribution locations:

Web: www.qorvo.com
Tel: 1-844-890-8163
Email: customer.support@qorvo.com

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